Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/686,728	TANAKA, TAKEHISA	
Examiner	Art Unit	
Sisay Yacob	2635	

	SEARCHED						
Class	Subclass	Date	Examiner				
340	870·07 3#1	03/14/06	s.Y.				
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	825-22 825-37						
702	178	03/14/06	5· <i>Y</i> .				
710	18 /	03/14/06	5·Y.				
340	\$	03/14/06	s.y.				
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
340	870.07 3.1	03/14/06	ς. γ.			
	3·3-3/ 825:22, 82	( 5:37 {	<b>\}</b>			
702	178	03/14/06	3.7.			
710	1	03/14/06	s Y			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Fast, Scarch. Tonaha in- To-koyoshi in	03/15/06	5 1/2		
time, general \$4 unit, first, second multiple, timb4				
Signal, Trunsmissi destination, modern measurment, Serie	les (			
bus, content Multi, point, data ocquisition, appared	tus ?			
Consulted Trin Edwards	, ,	, 54		
Albert Wom	03/13/06			
Jeffrey Hofsass	9/13/06			